Figure 1a



EEEEE GSPGPPGSPGPPGSPGPPGSPGPP EEEEE



PCT/US2004/043745

Figure 1b

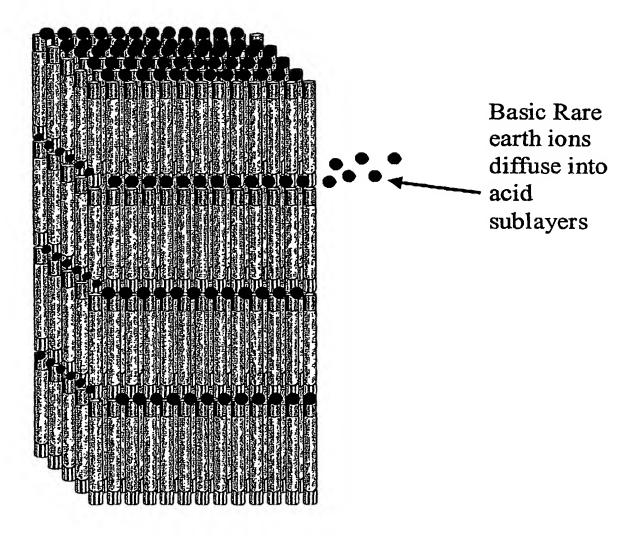


Figure 2a

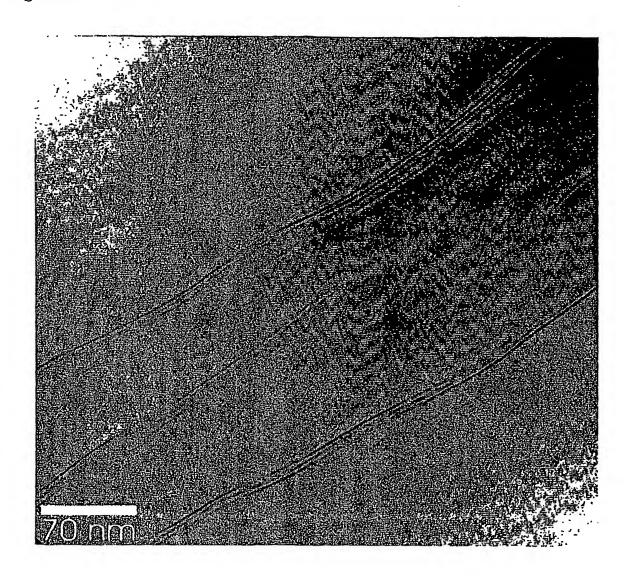


Figure 2b

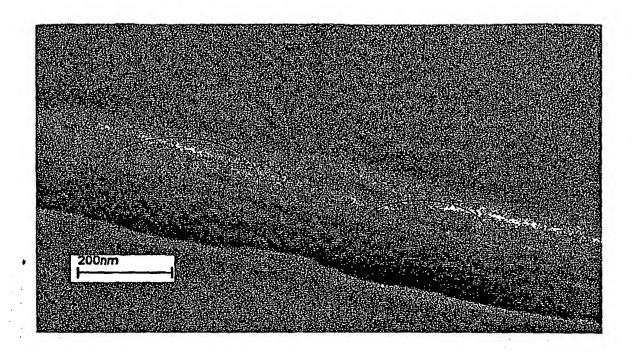


Figure 3a

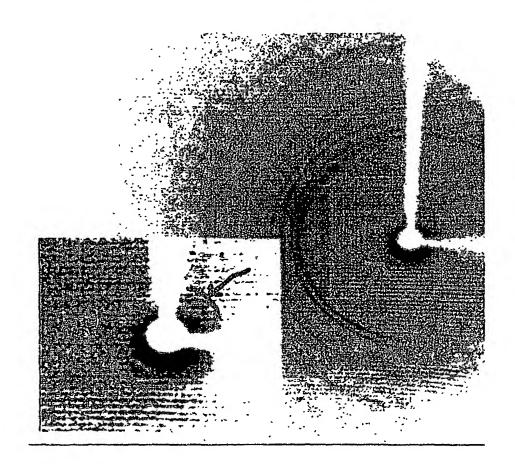
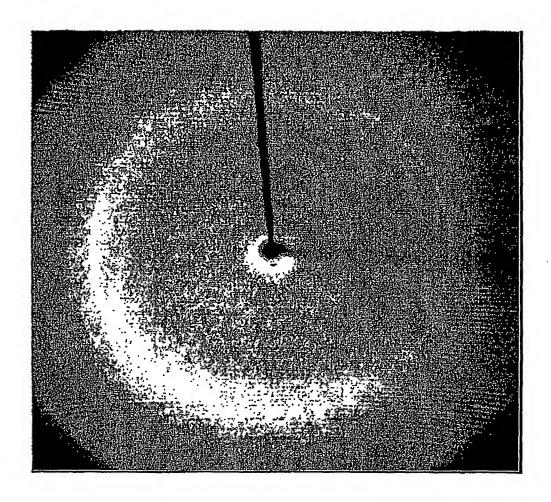
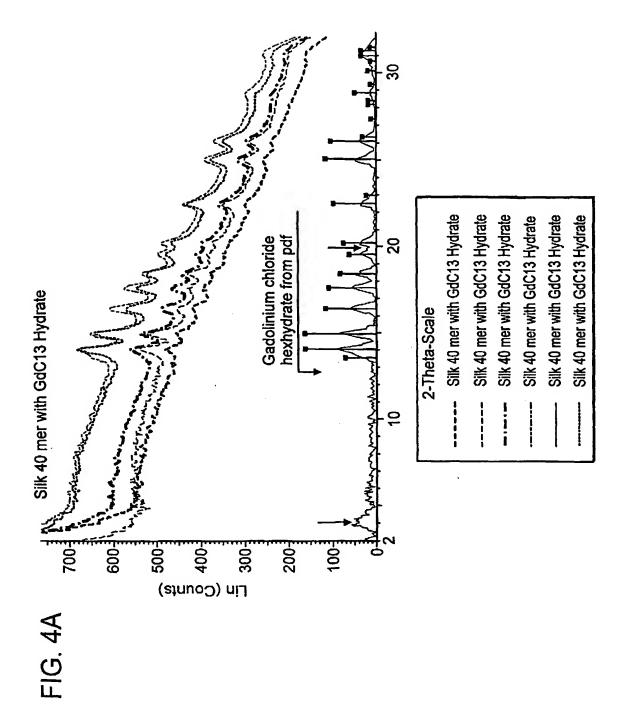


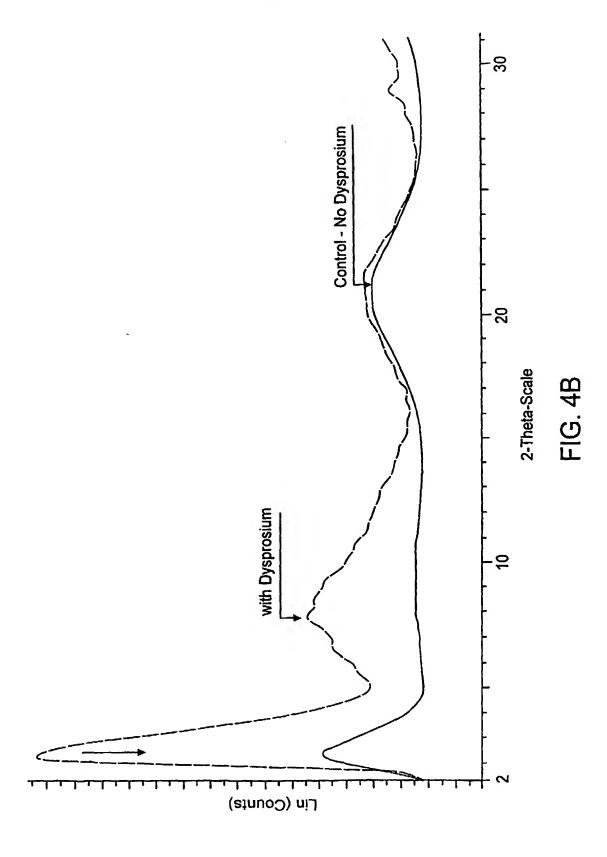
Figure 3b





SUBSTITUTE SHEET (RULE 26)





9/25

Figure 5a

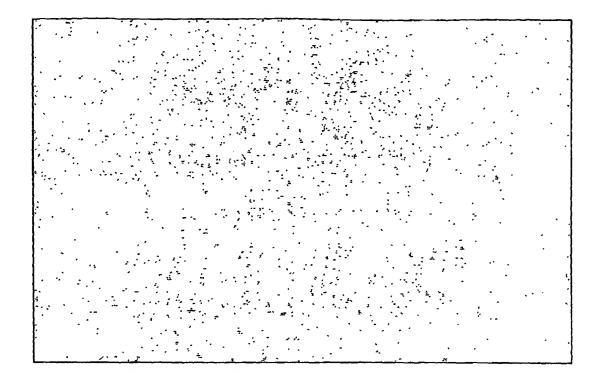


Figure 5b

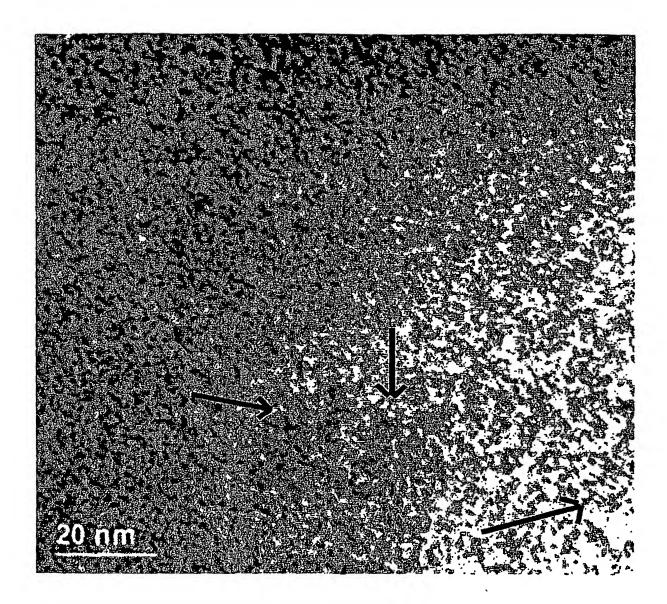


Figure 6a

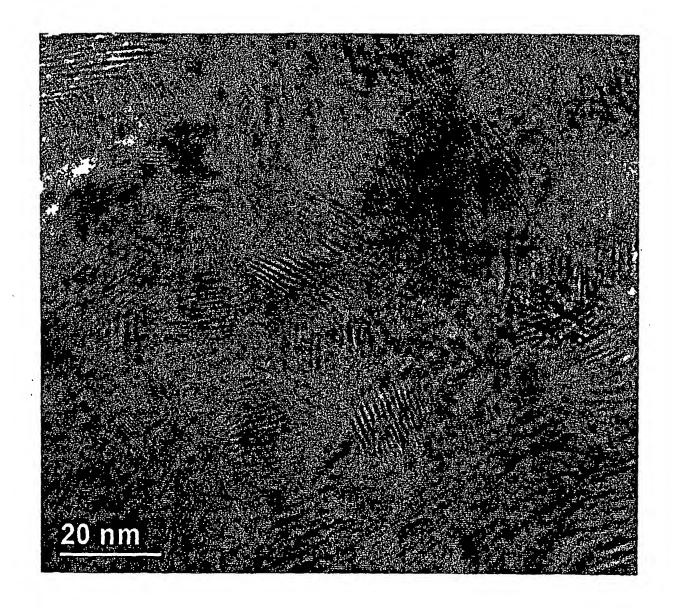
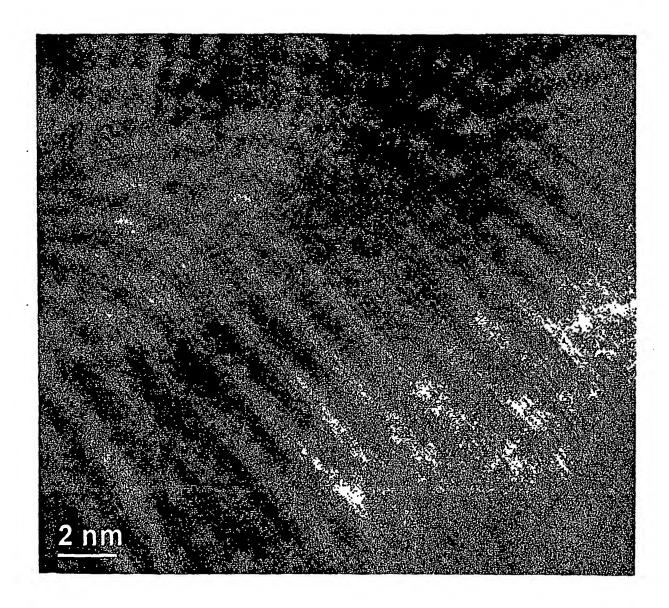
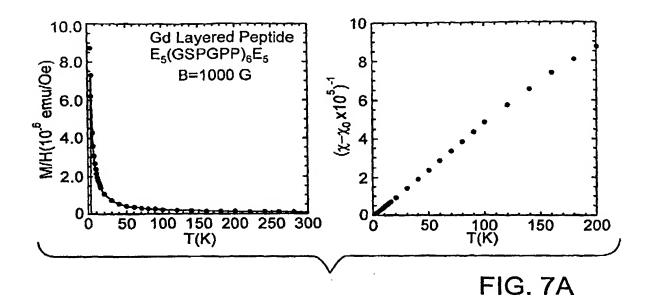
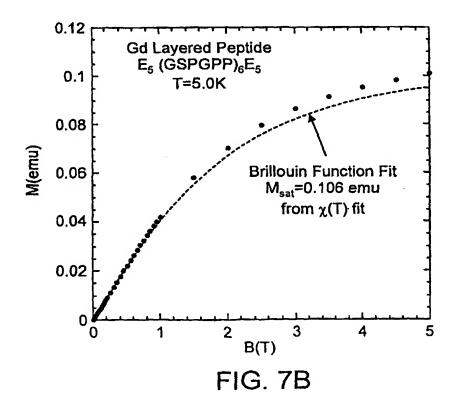


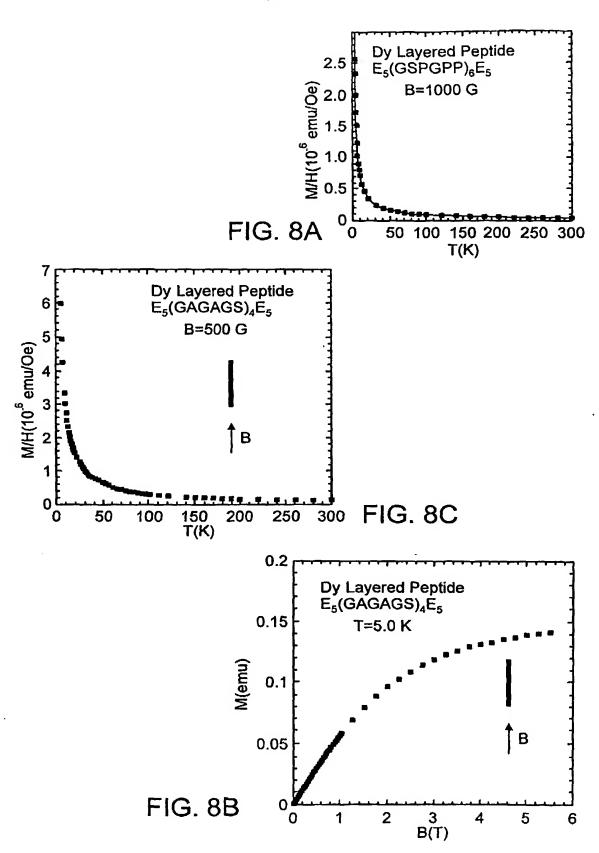
Figure 6b











SUBSTITUTE SHEET (RULE 26)

Figure 8d

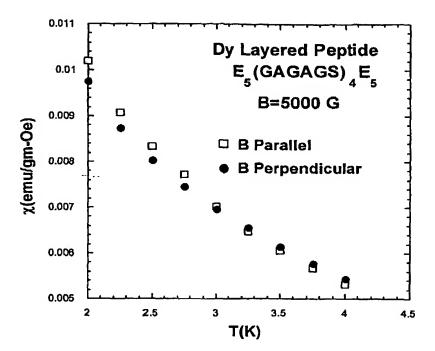
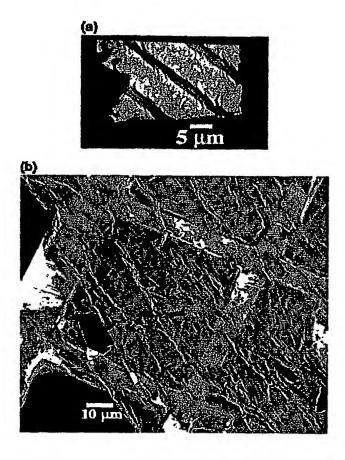


Figure 9



WO 2005/101993 PCT/US2004/043745

Figure 10

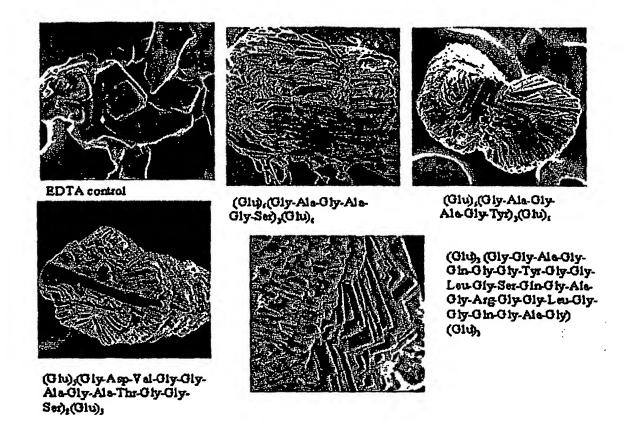
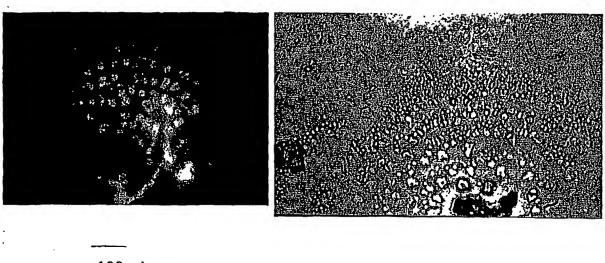


Figure 11



100 microns

Figure 12

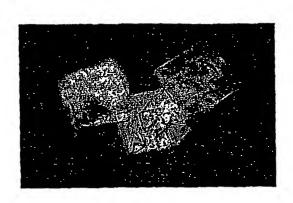
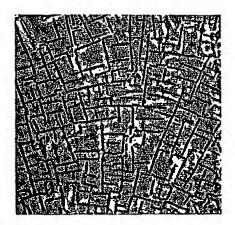


Figure 13



Figures 14a, b, and c

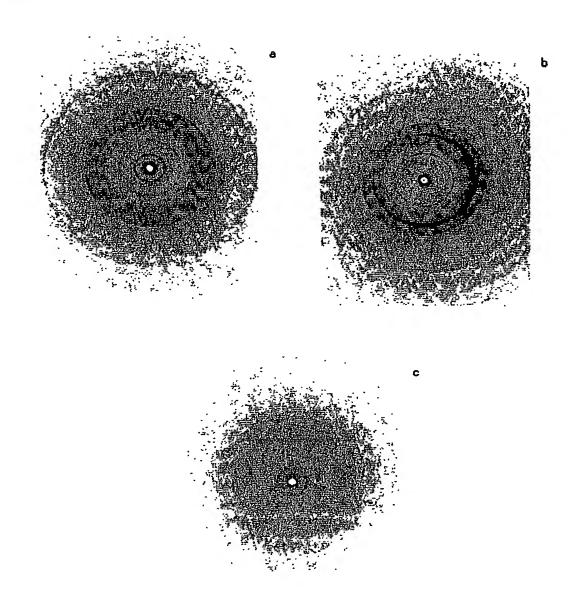


Figure 14d

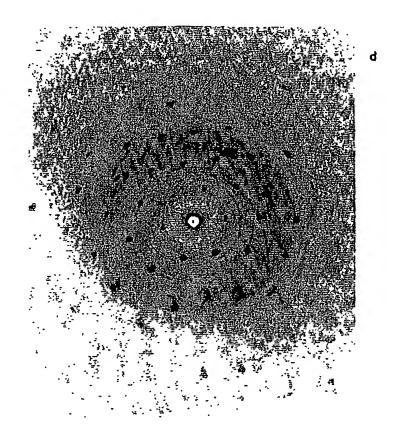


Figure 15

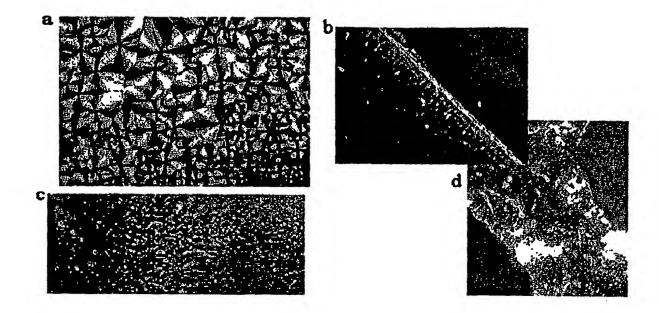


Figure 16

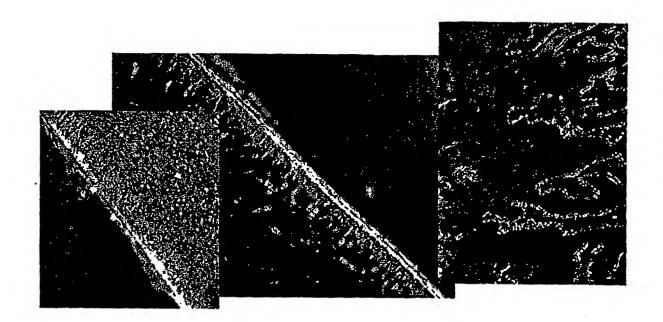


Figure 17

